INTERNATIONAL STANDARD

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Semiconductor devices –

Part 14-2:
Semiconductor sensors – Hall elements

Dispositifs à semiconducteurs –

Partie 14-2:
Capteurs à semiconducteurs – Eléments à effet de Hall

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CONTENTS

Page

FOREWORD 3
INTRODUCTION 4

Clause

1 General 5
1.1 Scope 5
1.2 Normative references 5
1.3 Definitions 5
1.4 Symbols 6
2 Essential ratings and characteristics 7
2.1 General 7
2.2 Ratings (limiting values) 8
2.3 Characteristics 8
3 Measuring methods 9
3.1 General 9
3.2 Output Hall voltage (V_H) 9
3.3 Offset voltage (V_o) 11
3.4 Input resistance (R_{in}) 12
3.5 Output resistance (R_{out}) 13
3.6 Temperature coefficient of output Hall voltage (α_{V_H}) 13
3.7 Temperature coefficient of input resistance (α_{Rin}) 14

INTERNATIONAL ELECTROTECHNICAL COMMISSION

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SEMICONDUCTOR DEVICES –

Part 14-2: Semiconductor sensors – Hall elements

FOREWORD

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International Standard IEC 60747-14-2 has been prepared by subcommittee 47E: Discrete semiconductor devices, of IEC technical committee 47: Semiconductor devices.

The text of this standard is based on the following documents:

FDIS	Report on voting
47E/158/FDIS	47E/171/RVD

Full information on the voting for the approval of this standard can be found in the report on voting indicated in the above table.

This publication has been drafted in accordance with the ISO/IEC Directives, Part 3.

The committee has decided that the contents of this publication will remain unchanged until 2005. At this date, the publication will be

- reconfirmed;
- withdrawn;
- replaced by a revised edition, or
- amended.

A bilingual version of this standard may be issued at a later date.

INTRODUCTION

This part of IEC 60747 should be read in conjunction with IEC 60747-1. It provides basic information on semiconductor

– terminology;
– letter symbols;
– essential ratings and characteristics;
– measuring methods;
– acceptance and reliability.

SEMICONDUCTOR DEVICES –

Part 14-2: Semiconductor sensors – Hall elements

1 General

1.1 Scope

This part of IEC 60747 provides standards for packaged semiconductor Hall elements which utilize the Hall effect.

1.2 Normative references

The following normative documents contain provisions which, through reference in this text, constitute provisions of this part of IEC 60747. For dated references, subsequent amendments to, or revisions of, any of these publications do not apply. However, parties to agreements based on this part of IEC 60747 are encouraged to investigate the possibility of applying the most recent editions of the normative documents indicated below. For undated references, the latest edition of the normative document referred to applies. Members of ISO and IEC maintain registers of currently valid International Standards.

IEC 60747-1:1983, *Semiconductor devices – Discrete devices and integrated circuits – Part 1: General*

IEC 61340-5-1:1998, *Electrostatics – Part 5-1: Protection of electronic devices from electrostatic phenomena – General requirements*